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From Silicon to Solutions: Getting the Right Memory Mix for the Application

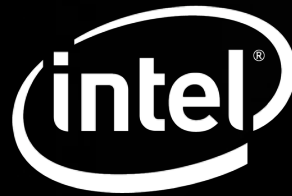
Ed Doller
Numonyx CTO

Flash Memory Summit 2008

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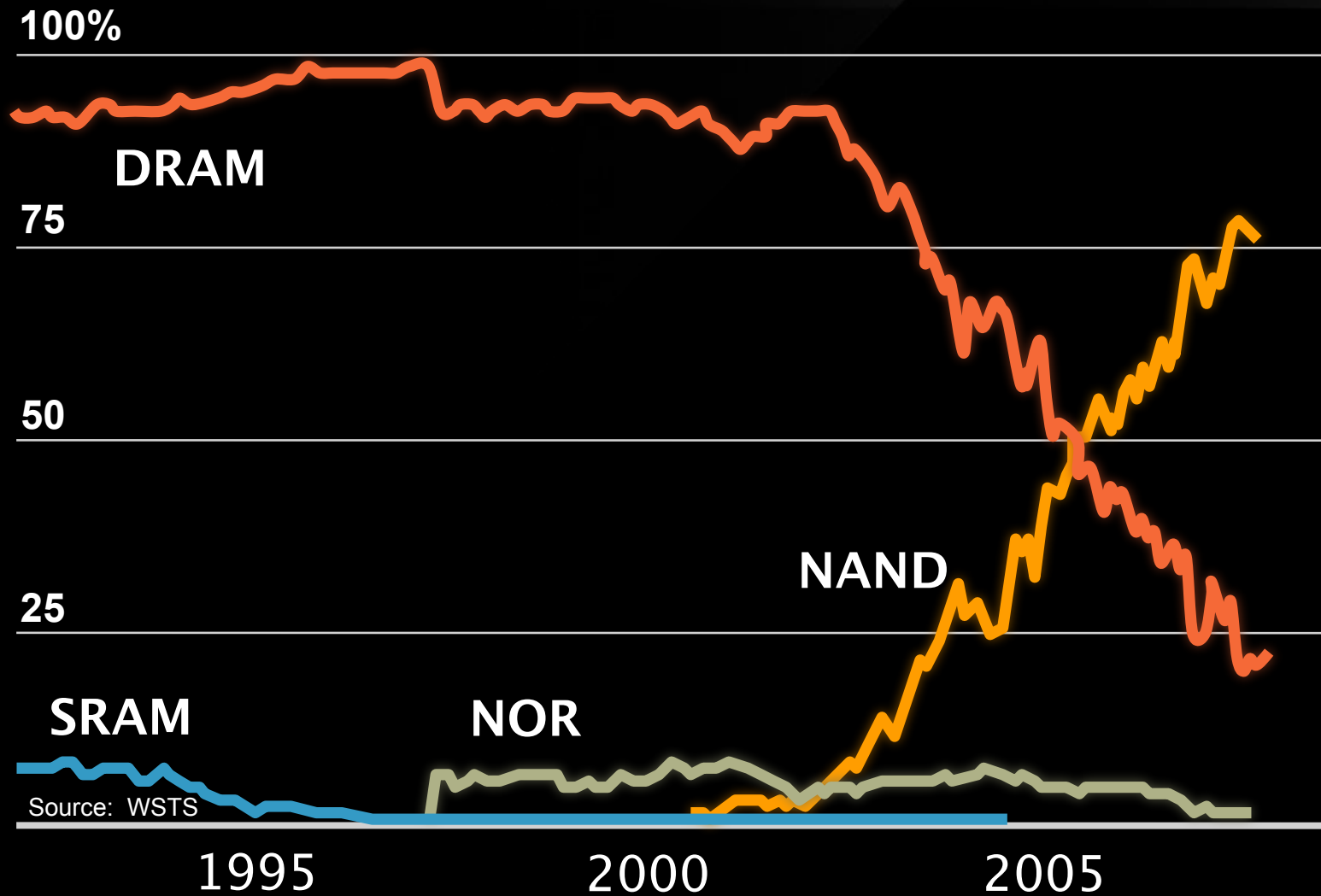
Numonyx Introduction



- A new company created by the contribution of non-volatile memory assets by STMicroelectronics and Intel with cash contributed by Francisco Partners
 - Ownership split ~49% / 45% / 6%
- First day of business March 31st, 2008
- Technology portfolio includes:

– NAND, NOR, PCM, RAM, Multi-chip solutions, & S/W

Bits as Percentage of Total

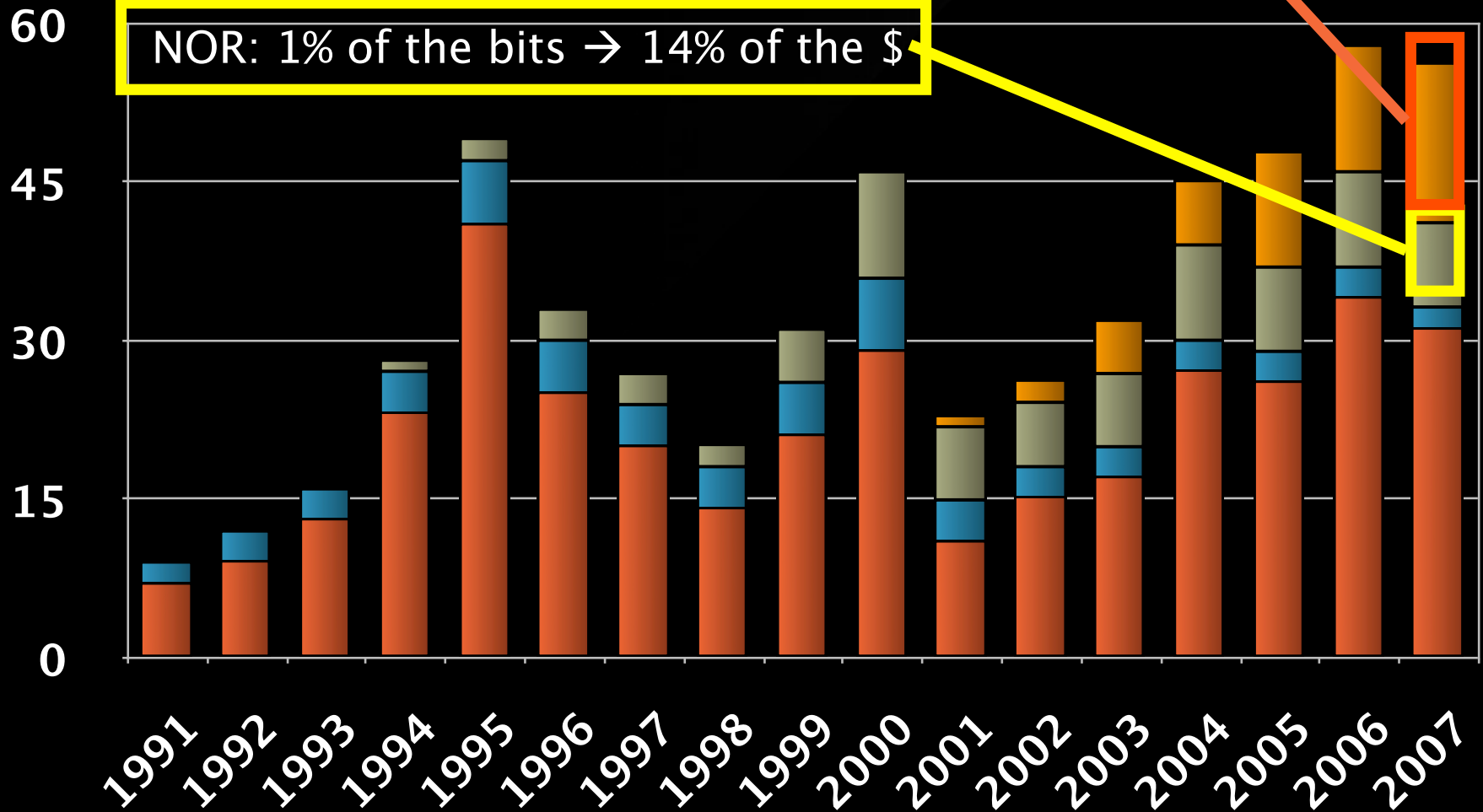


Source: WSTS

Memory Revenue

NAND: 75% of the bits \rightarrow 27% of the \$

NOR: 1% of the bits \rightarrow 14% of the \$



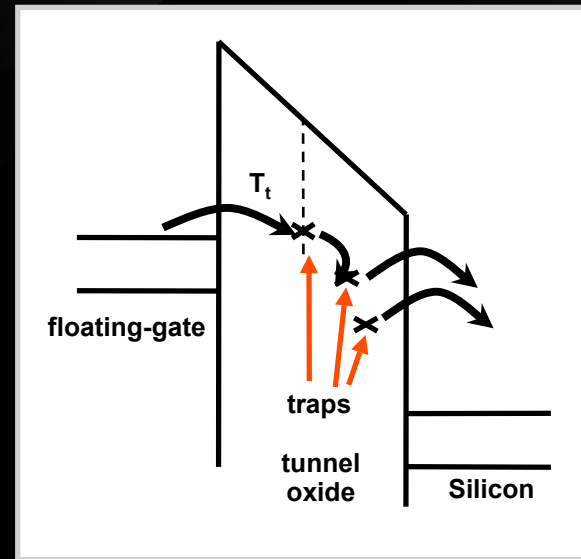
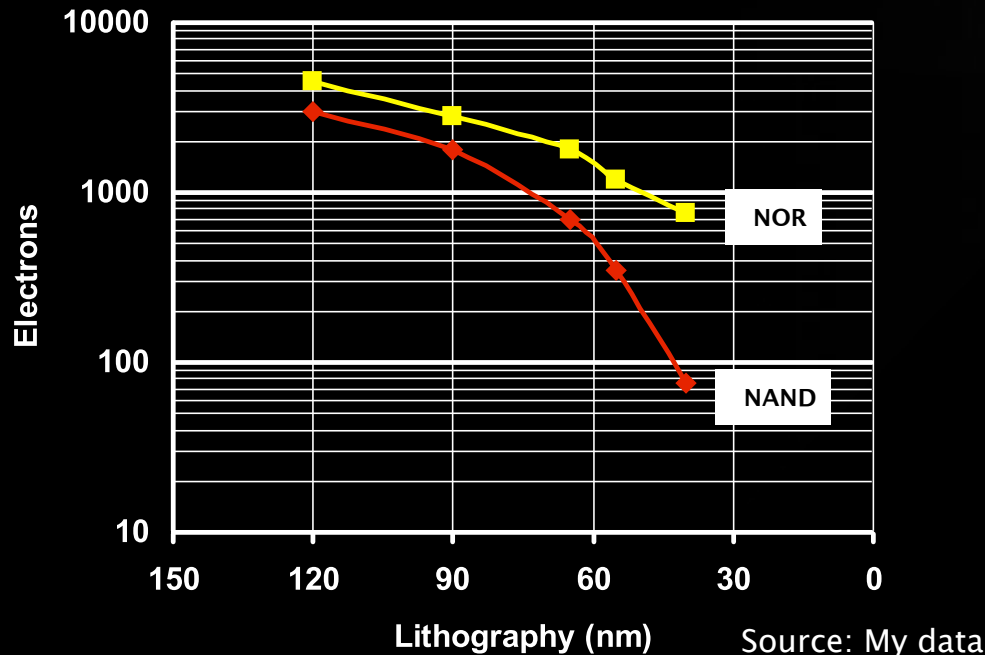
Source: WSTS, 2007 final

DRAM SRAM NOR
NAND

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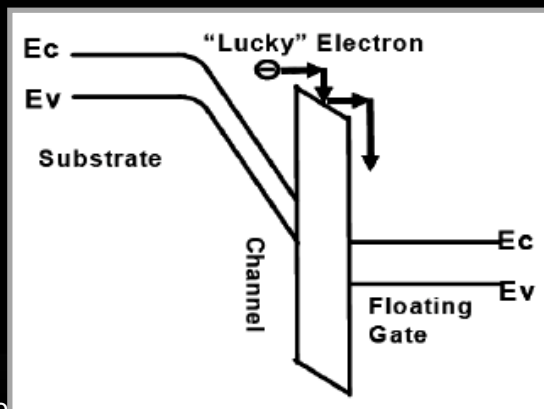
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Scaling & Reliability Challenges



NOR Reliability: Write / Erase
Tox traps leading to TAT or de-trapping of trapped oxide electrons

NAND Scaling & Reliability: Electrons



NOR (ETOX & NROM) Scaling:
3.2eV required to surmount Si-SiO₂ barrier → Limits Cell Gate Length Scaling

New Technologies

FRAM technology puts the “intelligence” in airbag systems

by by Duncan Bennett, Strategic Marketing Manager, Ramtron International Corp.
ECN Asia

Safety systems for automobiles are expected to become more sophisticated over the next several years. A principal driver of this trend is expected regulation which will impact system on the what to

Tuesday, Feb. 26 2008

Freescale MRAM Rockets into Space

BusinessWire
Comtex

NUREMBERG, Germany, Feb. 26, 2008 (BUSINESS WIRE) – Freescale Semiconductor, the leading provider of memory for automotive, industrial, and board a

Phase change memory prototypes released

5 March 2008

Intel and STMicroelectronics reached a key industry milestone recently as they began shipping prototype samples of a future product using a new, innovative memory technology called phase change memory (PCM). The prototypes are the first functional silicon to be delivered to customers for evaluation, bringing the technology one step closer to adoption.

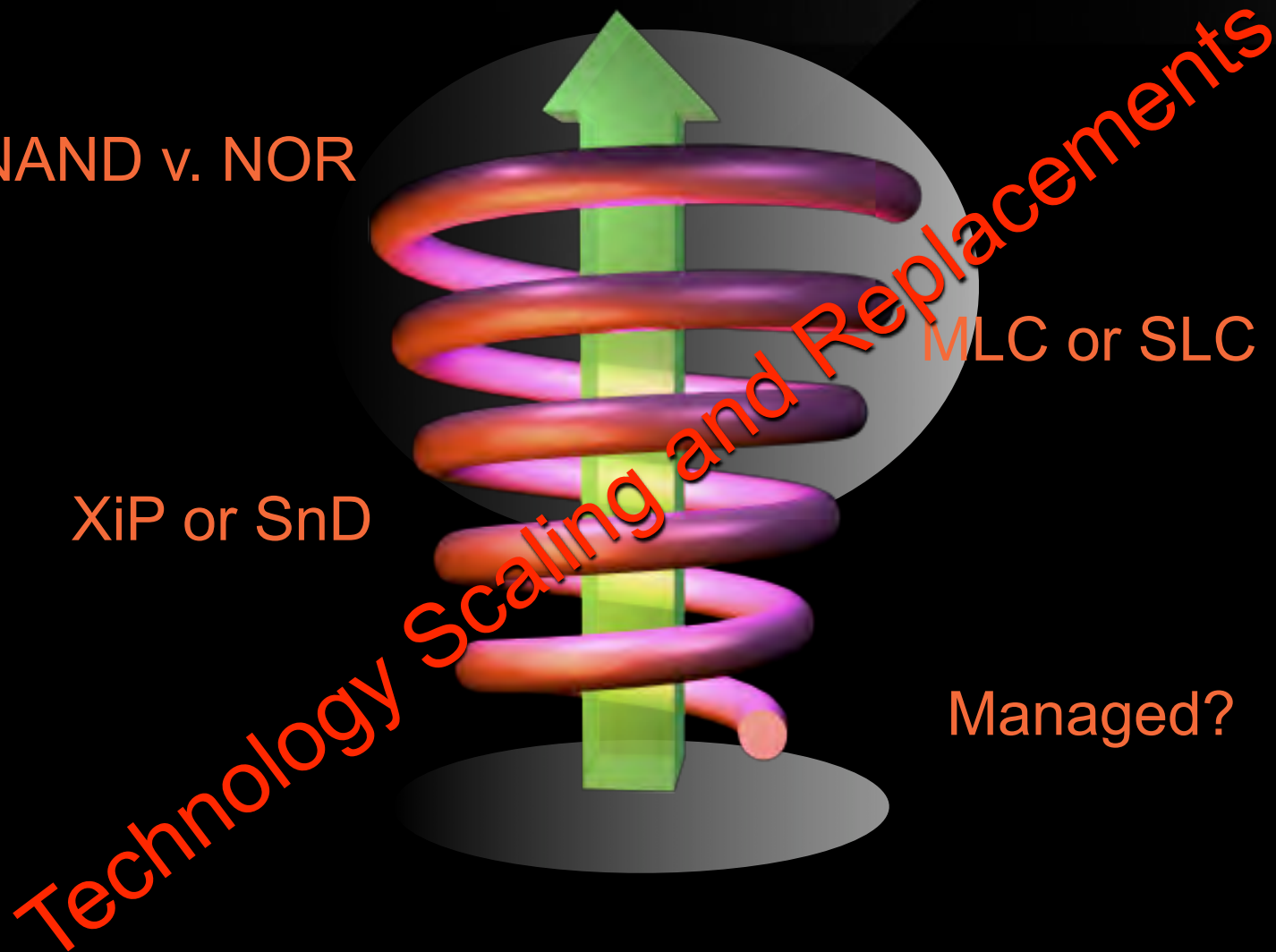
Chaos

NAND v. NOR

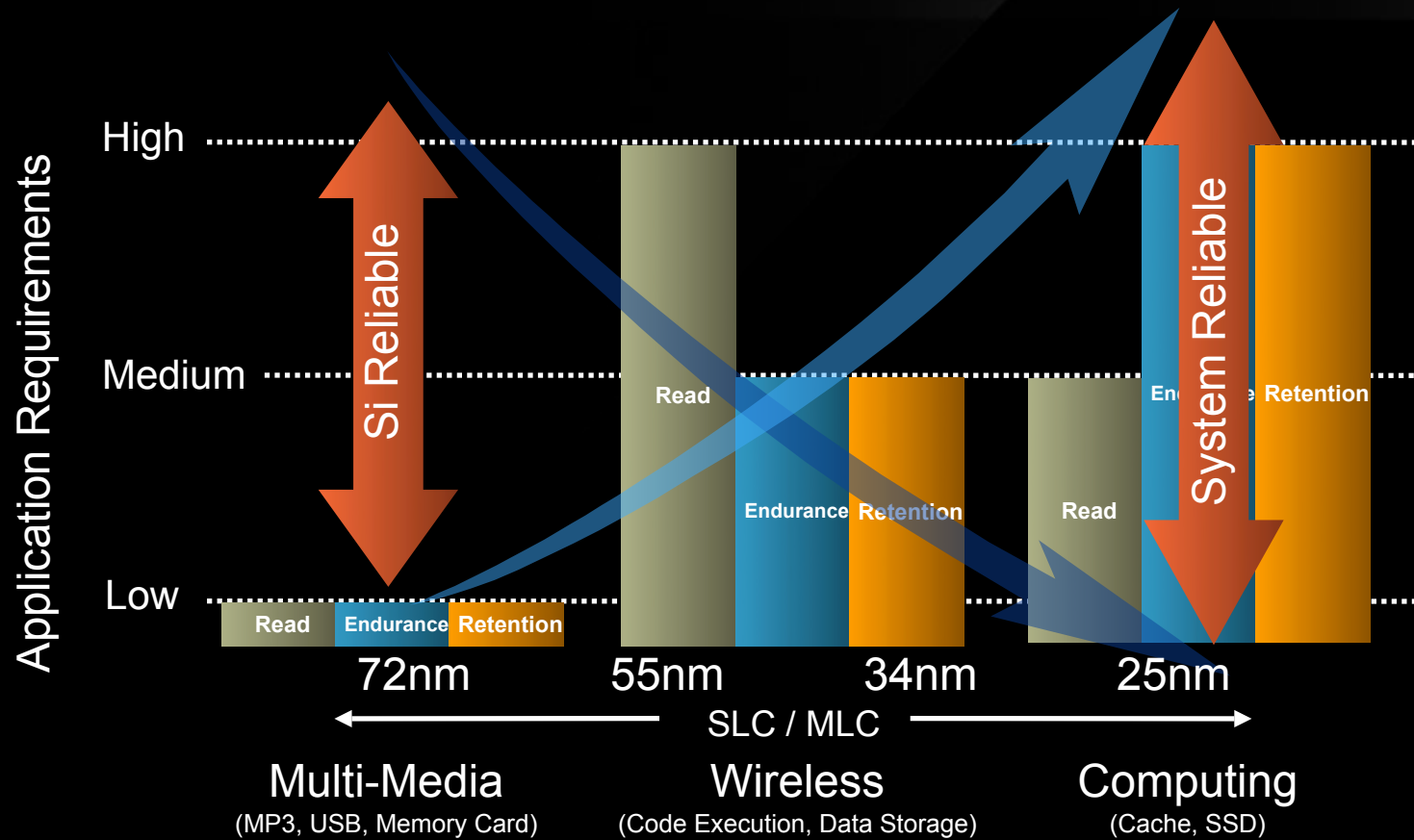
XiP or SnD

MLC or SLC

Managed?



Technology & Application



Application specific system solutions required as technology scales → Higher Cost

Technology Capability Assessment

Attributes

PCM

EEPROM

NOR

NAND

DRAM

Technology Capability Assessment

Attributes	PCM	EEPROM	NOR	NAND	DRAM
Non-Volatile	Yes	Yes	Yes	Yes	No

Technology Capability Assessment

Attributes	PCM	EEPROM	NOR	NAND	DRAM
Non-Volatile	Yes	Yes	Yes	Yes	No
Clear Scaling to	15 nm	?	32 nm	32 nm	32 nm

Technology Capability Assessment

Attributes	PCM	EEPROM	NOR	NAND	DRAM
Non-Volatile	Yes	Yes	Yes	Yes	No
Clear Scaling to	15 nm	?	32 nm	32 nm	32 nm
Blk Granularity	Small/Byte	Small/Byte	Large	Large	Small/Byte

Technology Capability Assessment

Attributes	PCM	EEPROM	NOR	NAND	DRAM
Non-Volatile	Yes	Yes	Yes	Yes	No
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Byte/Bit Write	Yes	Yes	Yes	# of Ops	Yes

Technology Capability Assessment

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Erase Required	No	No	Yes	Yes	No

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Erase Required	No	No	Yes	Yes	No
Software	Easy	Easy	Moderate	Hard	Easy

Technology Capability Assessment

Attributes	PCM	EEPROM	NOR	NAND	DRAM
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Blk Granularity	Small/Byte	Small/Byte	Large	Large	Small/Byte
Byte/Bit Write	Yes	Yes	Yes	# of Ops	Yes
Erase Required	No	No	Yes	Yes	No
Software	Easy	Easy	Moderate	Hard	Easy
Power	~Flash	~Flash	~Flash	~Flash	High

Technology Capability Assessment

Attributes	PCM	EEPROM	NOR	NAND	DRAM
Non-Volatile	Yes	Yes	Yes	Yes	No
Clear Scaling to	15 nm	?	32 nm	32 nm	32 nm
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Byte/Bit Write	Yes	Yes	Yes	# of Ops	Yes
Erase Required	No	No	Yes	Yes	No
Software	Easy	Easy	Moderate	Hard	Easy
Power	~Flash	~Flash	~Flash	~Flash	High
Write Bandwidth	1- 15+MB/s	13-30KB/s	0.5-2 MB/s	10+ MB/s	100s+MB/s

Technology Capability Assessment

Attributes	PCM	EEPROM	NOR	NAND	DRAM
Non-Volatile	Yes	Yes	Yes	Yes	No
Clear Scaling to	15 nm	?	32 nm	32 nm	32 nm
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Software	Easy	Easy	Moderate	Hard	Easy
Power	~Flash	~Flash	~Flash	~Flash	High
Write Bandwidth	1- 15+MB/s	13-30KB/s	0.5-2 MB/s	10+ MB/s	100s+MB/s
Read Latency	50 - 100 ns	200-200ns	70-100 ns	15-50 μ s	20 - 80 ns

Technology Capability Assessment

PCM: Lower Theoretical Cost & Power

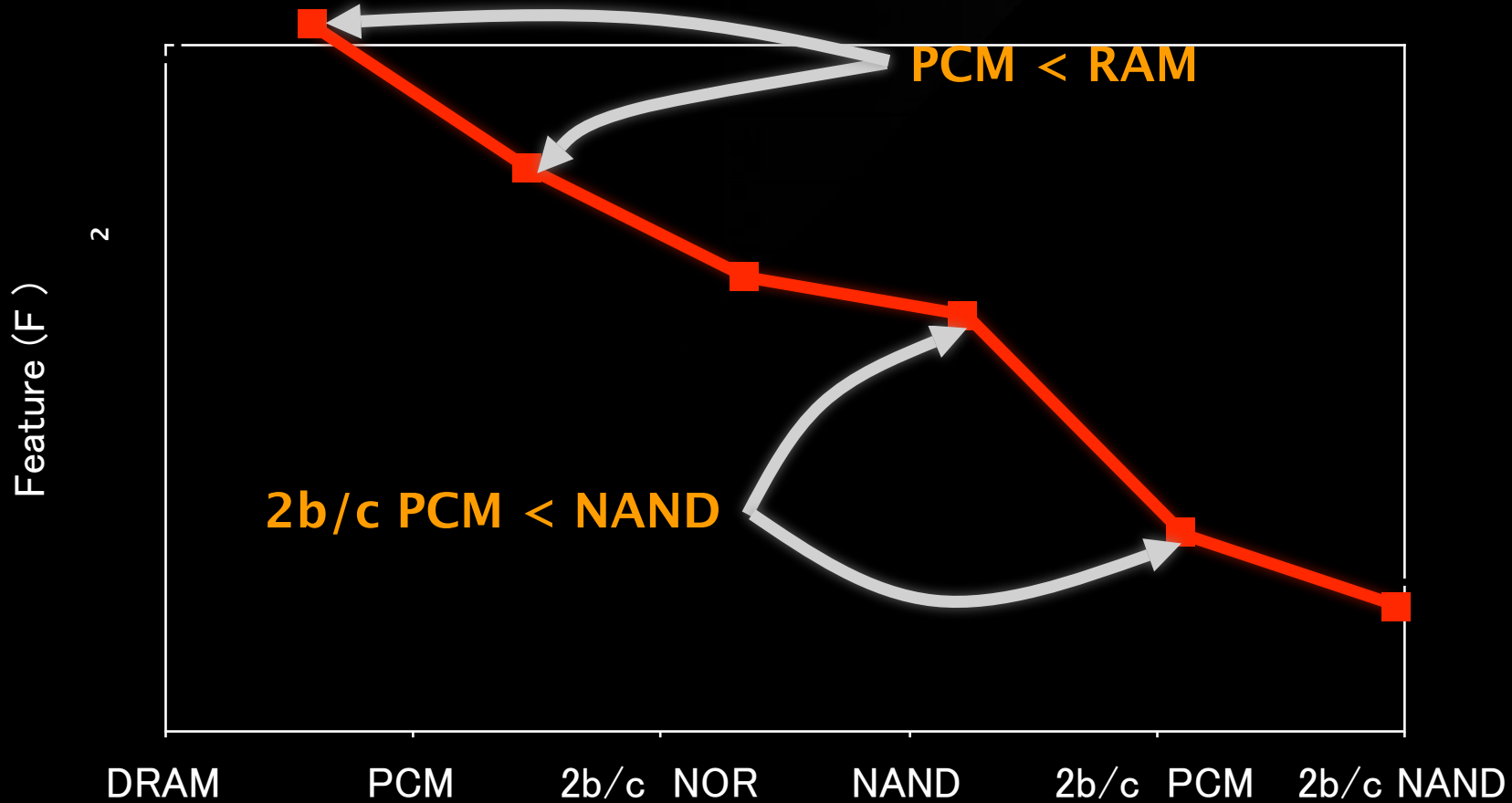
PCM: Scalability, bit alterable,
endurance

PCM: Much Lower
Cost & Much Faster Writes

Attributes	PCM	EEPROM	NOR	NAND	DRAM
Non-Volatile	Yes	Yes	Yes	Yes	No
Clear Scaling to	15 nm	?	32 nm	32 nm	32 nm
Blk Granularity	Small/Byte	Small/Byte	Large	Large	Small/Byte
Byte/Bit Write	Yes	Yes	Yes	# of Ops	Yes
Erase Required	No	No	Yes	Yes	No
Software	Easy	Easy	Moderate	Hard	Easy
Power	~Flash	~Flash	~Flash	~Flash	High
Write Bandwidth	1- 15+MB/s	13-30KB/s	0.5-2 MB/s	10+ MB/s	100s+MB/s
Read Latency	50 - 100 ns	200-200ns	70-100 ns	15-50 μ s	20 - 80 ns
Endurance	10 ⁶⁺	10 ⁵ -10 ⁶	10 ⁵	10 ⁴⁻⁵	Unlimited

Technology Cost Comparison

40nm 1/2 Pitch Comparison



Cost comes in many forms...

- The obvious ones

- Technology, litho, manufactur



ASP

- The not so obvious ones

- Time-to-market → Ease of use

- S/W changes

- Reliability Challenges → Usage Models

- Manageability → Controller



Hidden

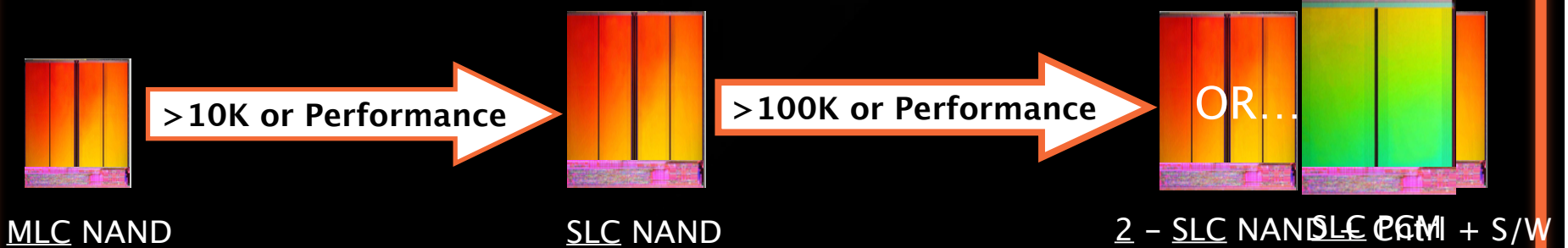
- System Level Costs



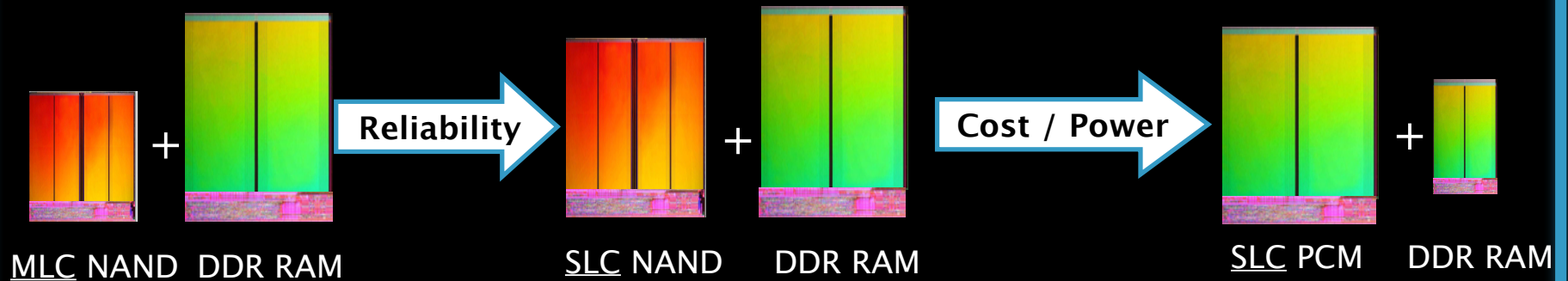
BOM

System Level Cost

Example #1: Data Solution – High Performance or High



Example #2: Low Power Code Solution



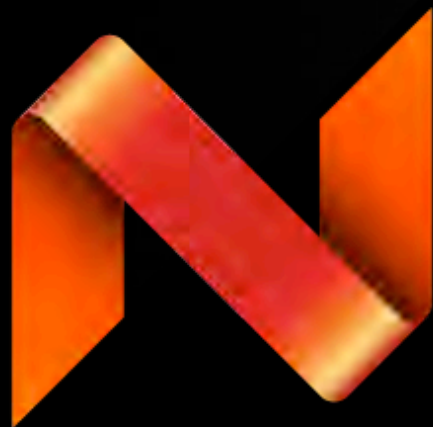
Summary: What Does This Mean for Us?

Customers

1. Understand Usage
2. Understand True Cost
3. Work with a Trustworthy Supplier
4. Get your PCM Samples NOW...

Suppliers

1. Provide Technology Transparency
2. S/W & Systems Expertise
3. Si & Solution Standards
4. PCM is the future, lets standardize...



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